

IBIST™ (Interconnect Built-in Self-Test) Architecture and Methodology for PCI Express: Intel's Next-Generation Test and Validation Methodology for Performance IO

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Abstract

This paper summarizes the test challenges associated with next-generation platform buses and introduces an Intel-developed technology called IBIST™ (Interconnect Built-In Self-Test) created to meet those challenges. The IBIST™ testing methodology and associated on-die architecture customized for PCI Express (PCIe) interface is described.

This paper was submitted under the ITC Special Board and System Test Call-for-Papers that had an extended due-date. As such, the full text of the paper was not available in time for inclusion in the general volume of the 2003 ITC Proceedings. The full text is available in *2003 ITC Proceedings—Board and System Test Track*.